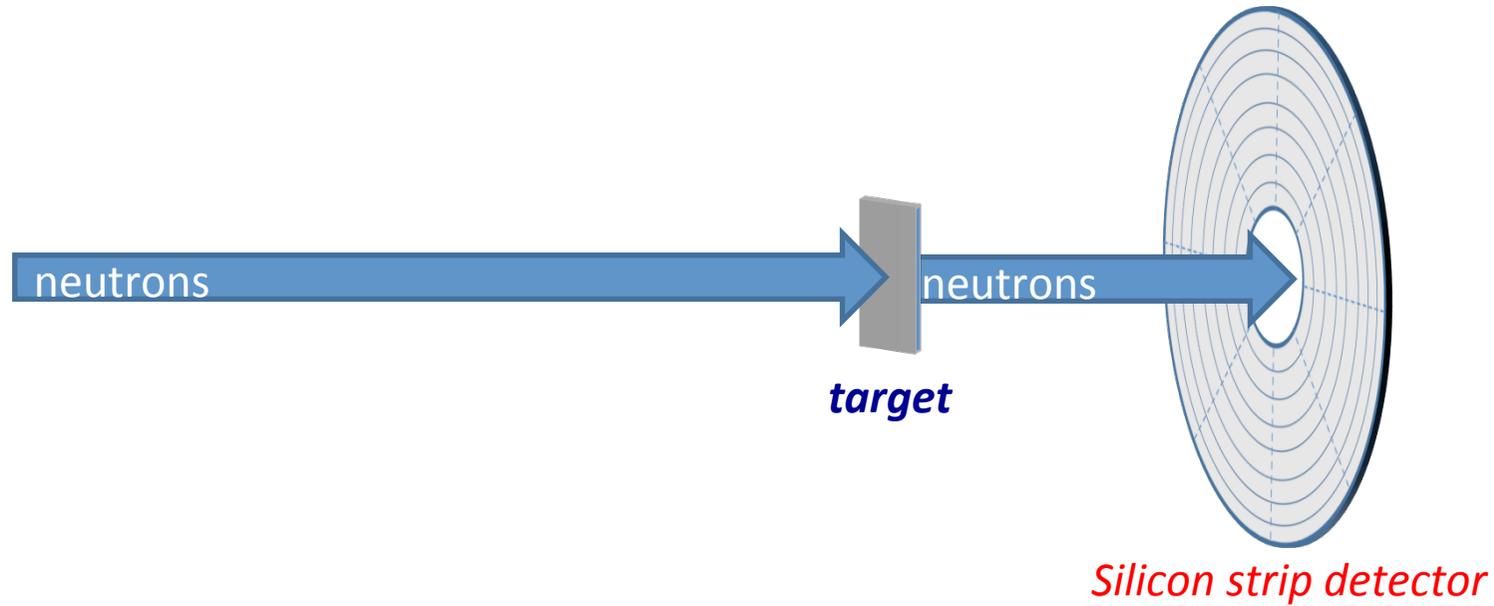
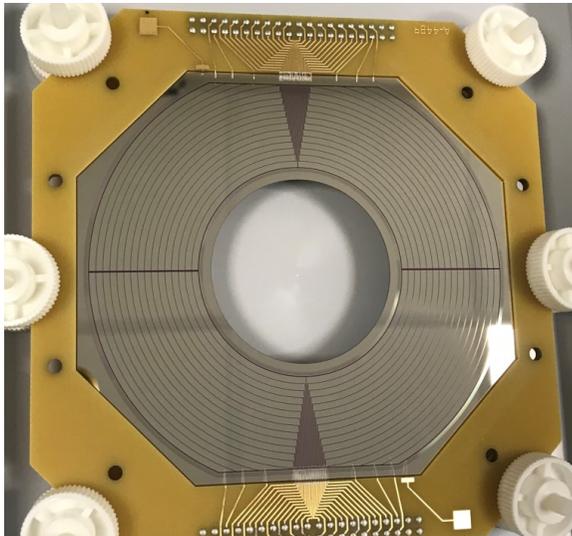
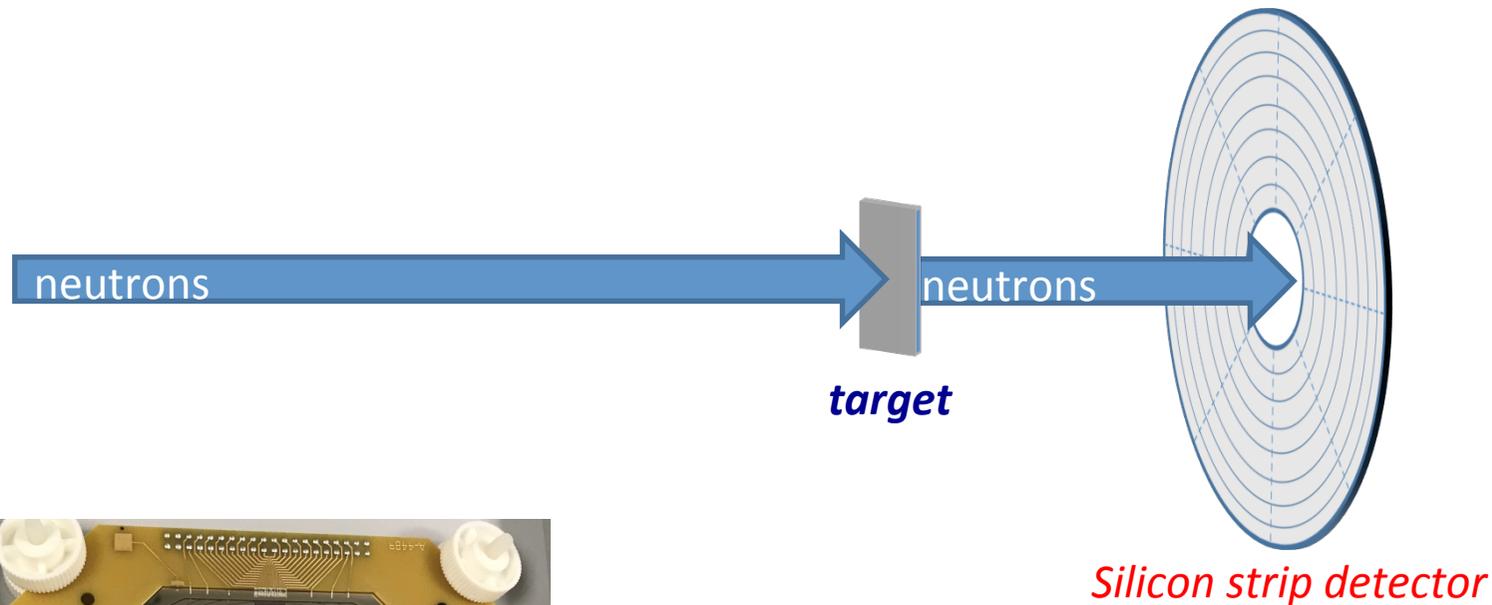




# New detectors for (n,cp) measurements.



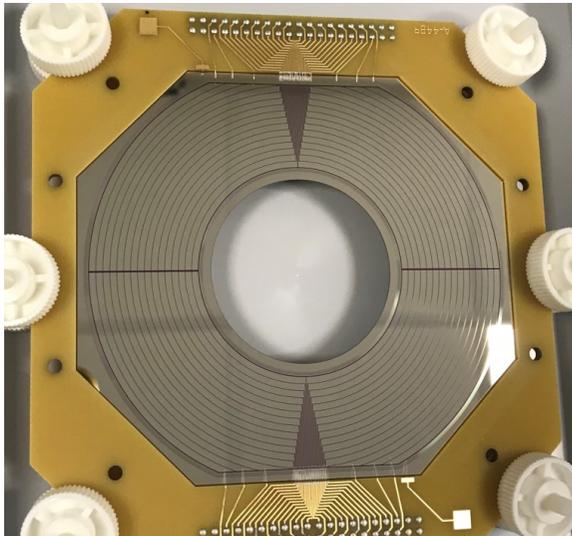
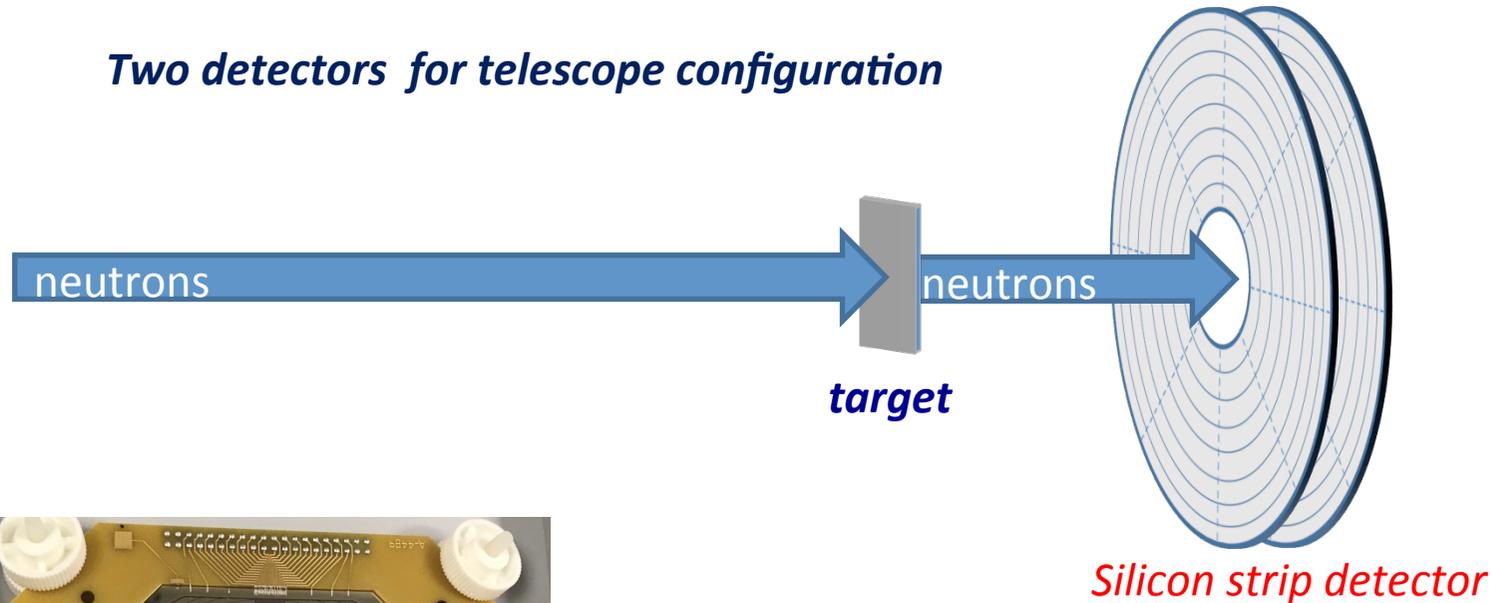


## Micron Semiconductor

- Thickness: 300  $\mu\text{m}$
- Outer Diameter: 96 mm
- Central Hole: 46 mm
- No of Rings (Junction): 16
- No of Elements (Junction): 64
- No of Sectors (Ohmic): 16

## Particle Discrimination

*Two detectors for telescope configuration*

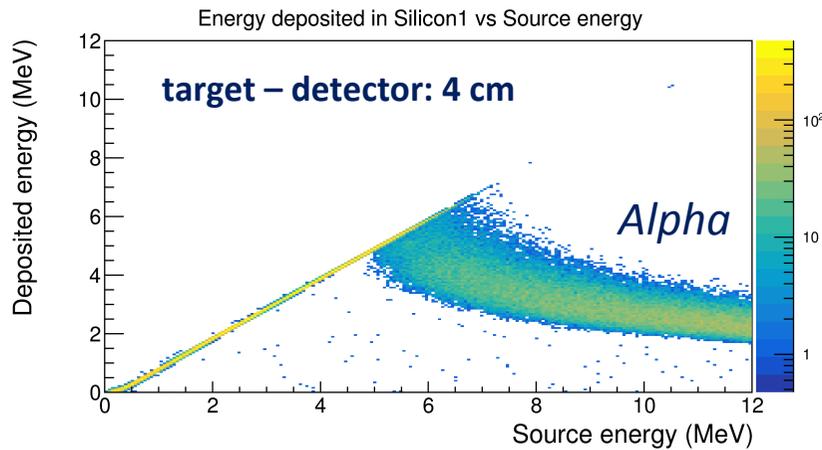
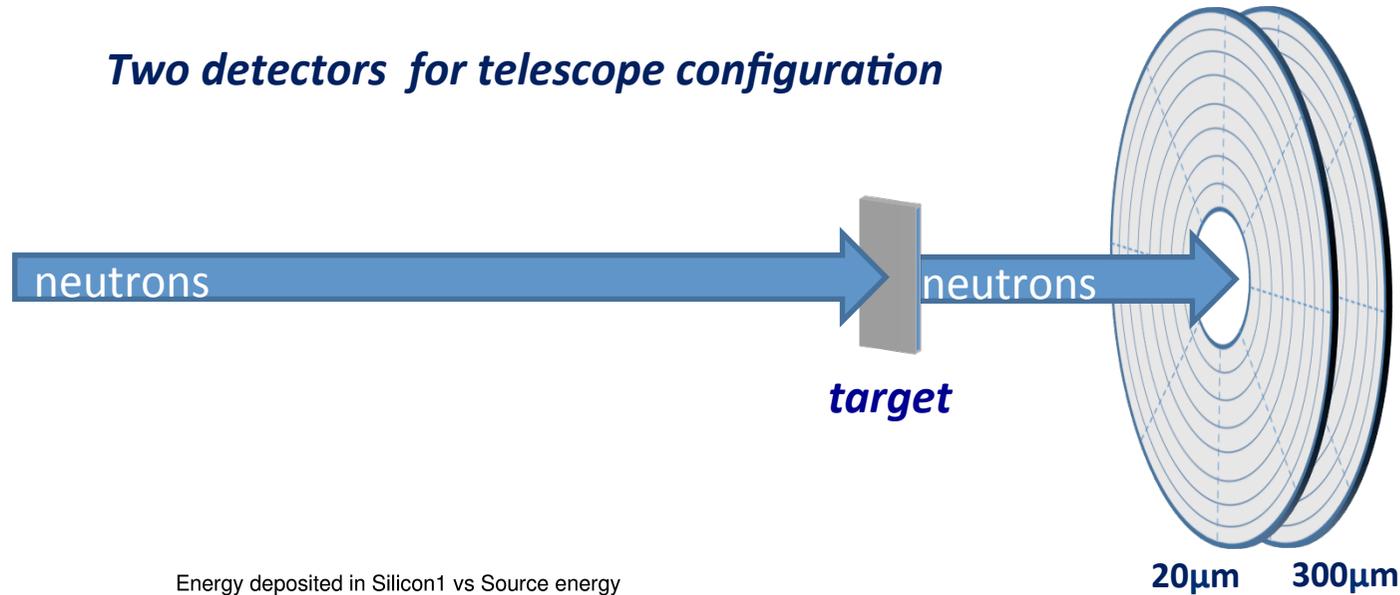


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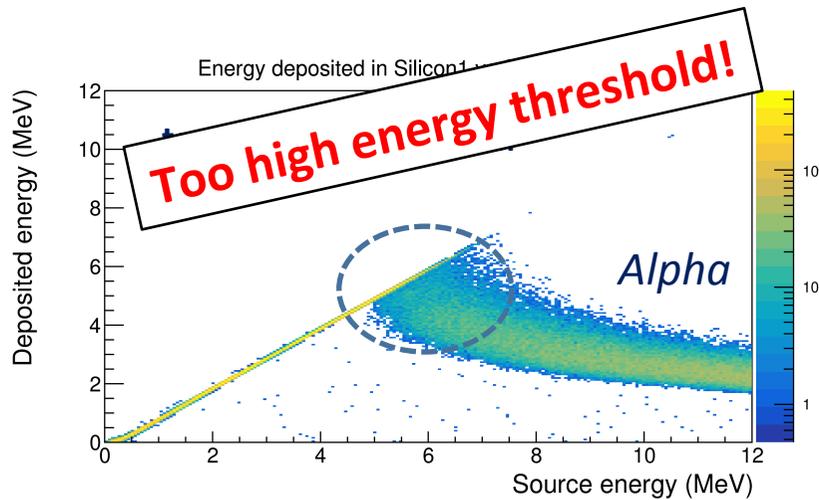
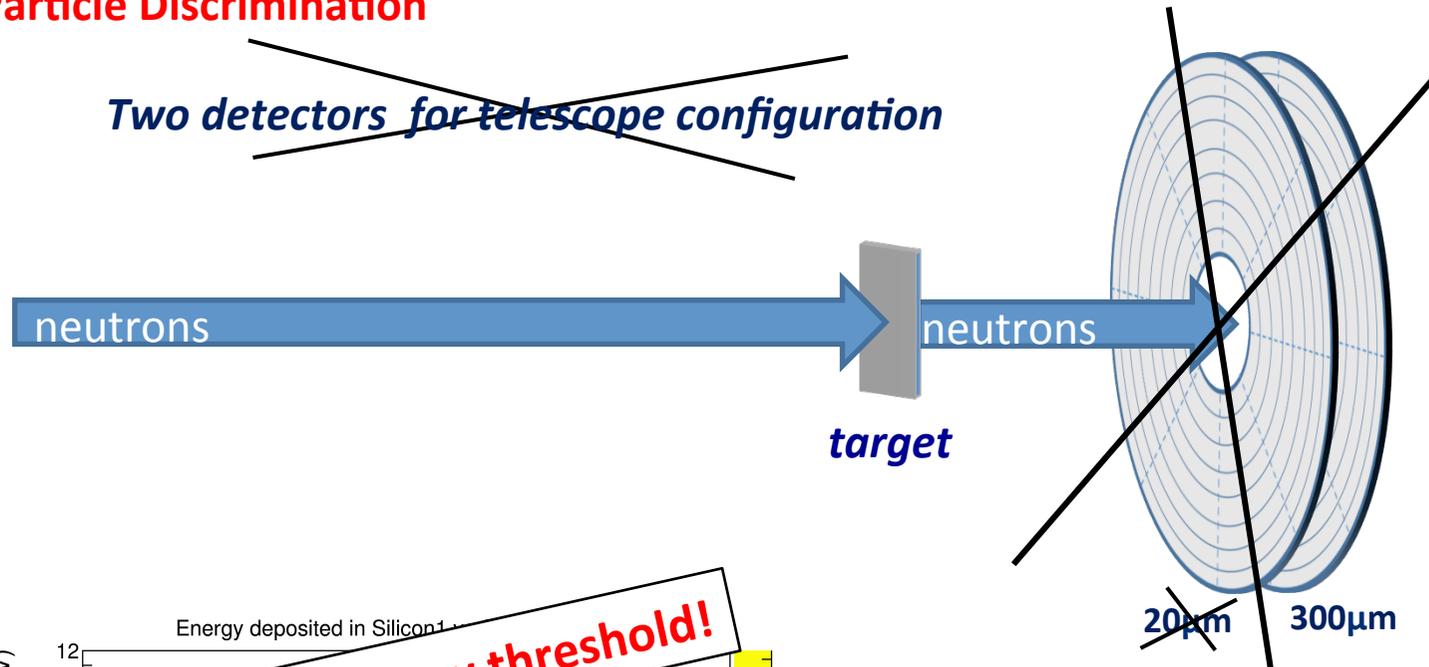


1st detector	Telescope
<b>11%</b>	<b>6 %</b>

Alpha efficiency (< 12MeV)

## Particle Discrimination

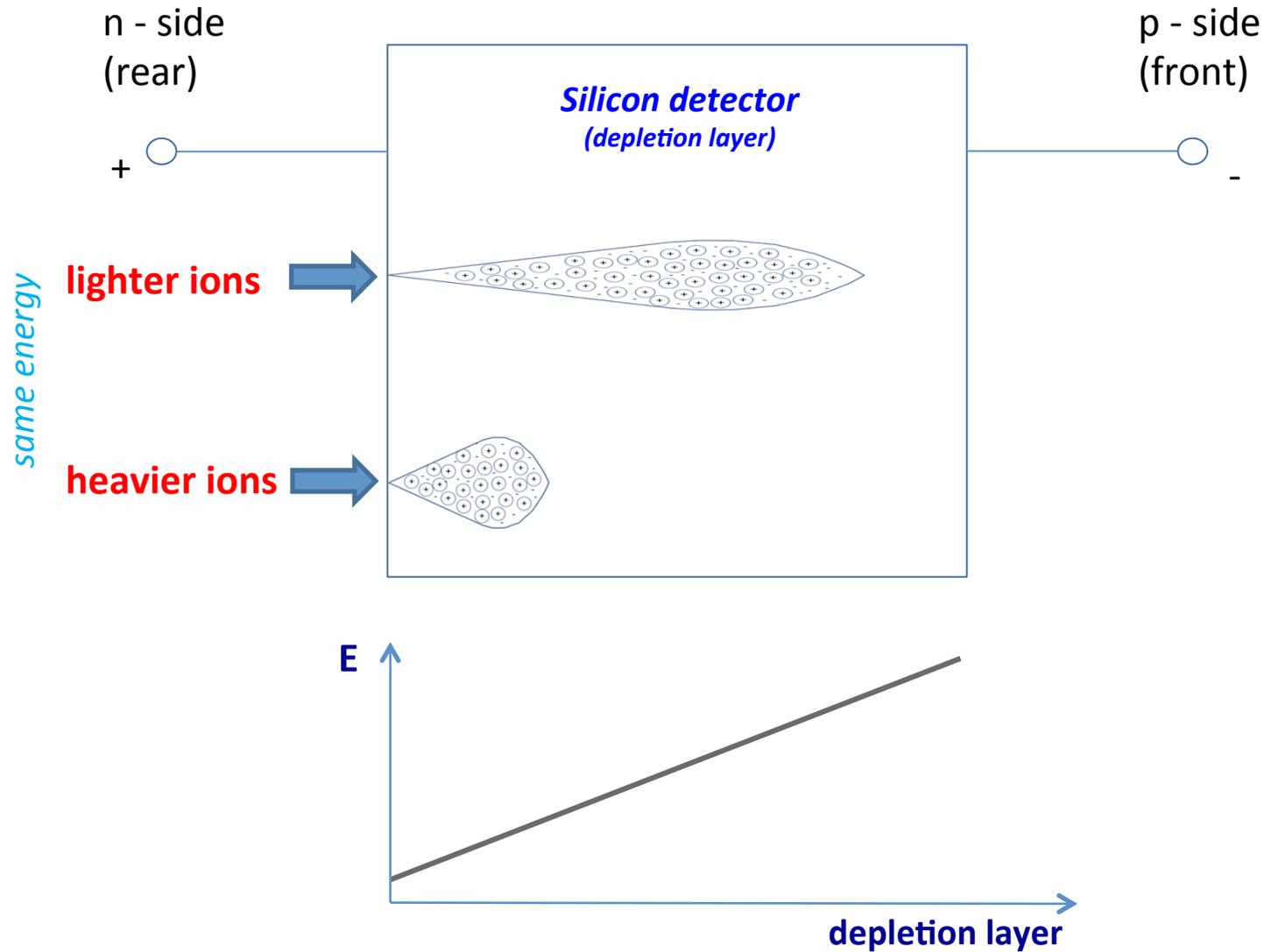
~~Two detectors for telescope configuration~~



1st detector	Telescope
11%	6%

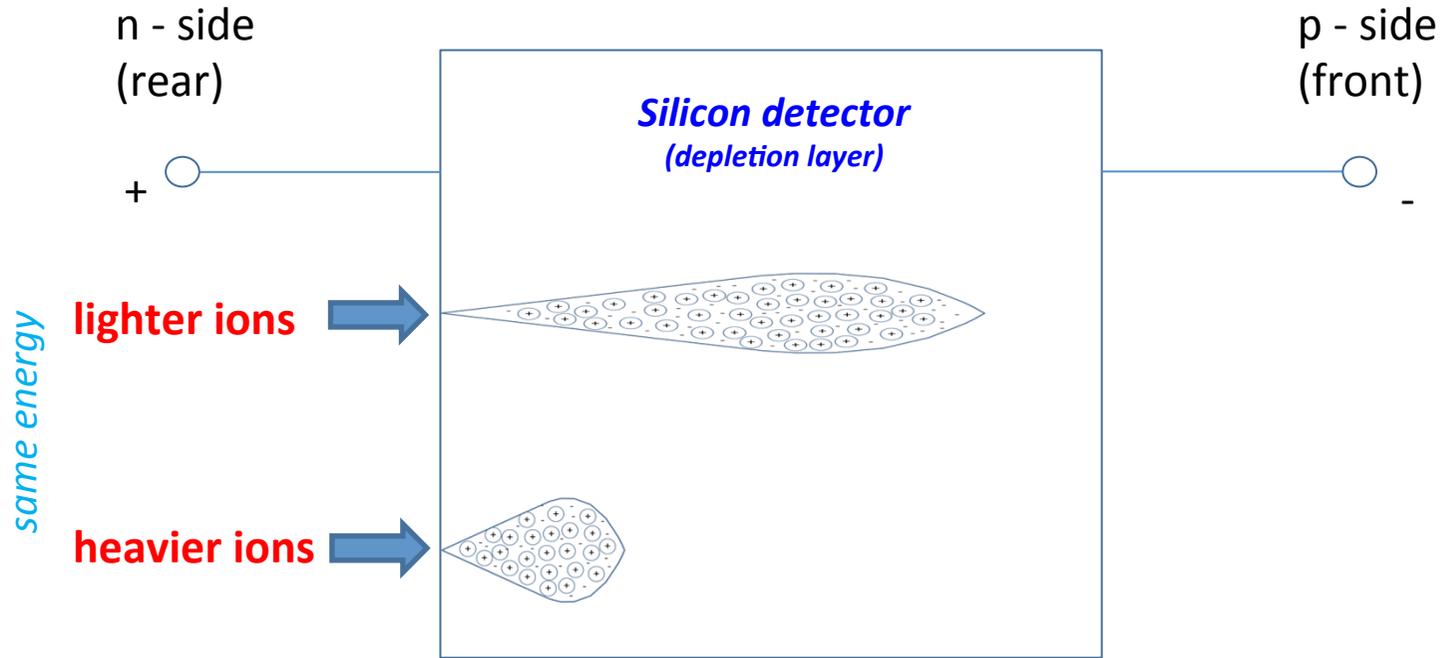
Alpha efficiency (< 12MeV)

## Particle discrimination by rear side injection mode

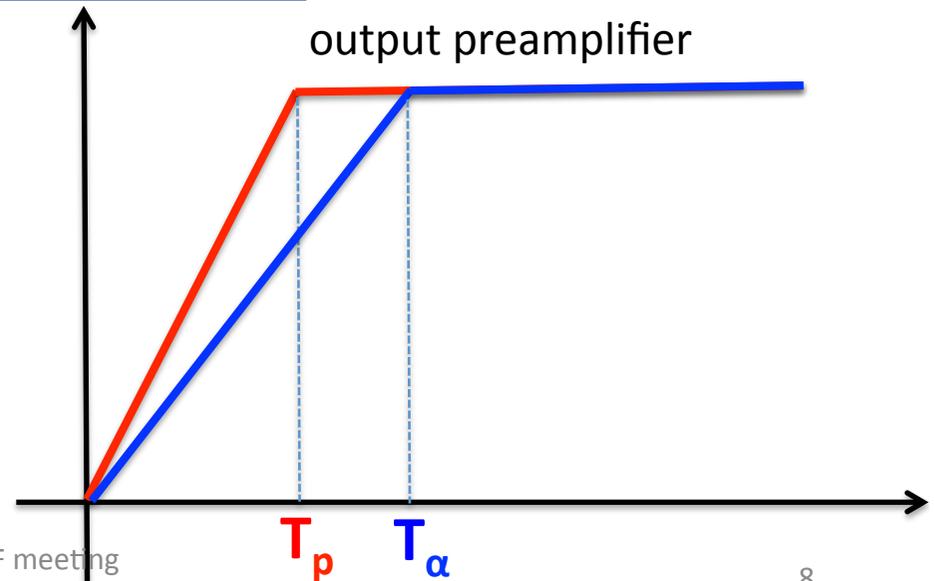


The charge collection time **affects** the shape of the signal

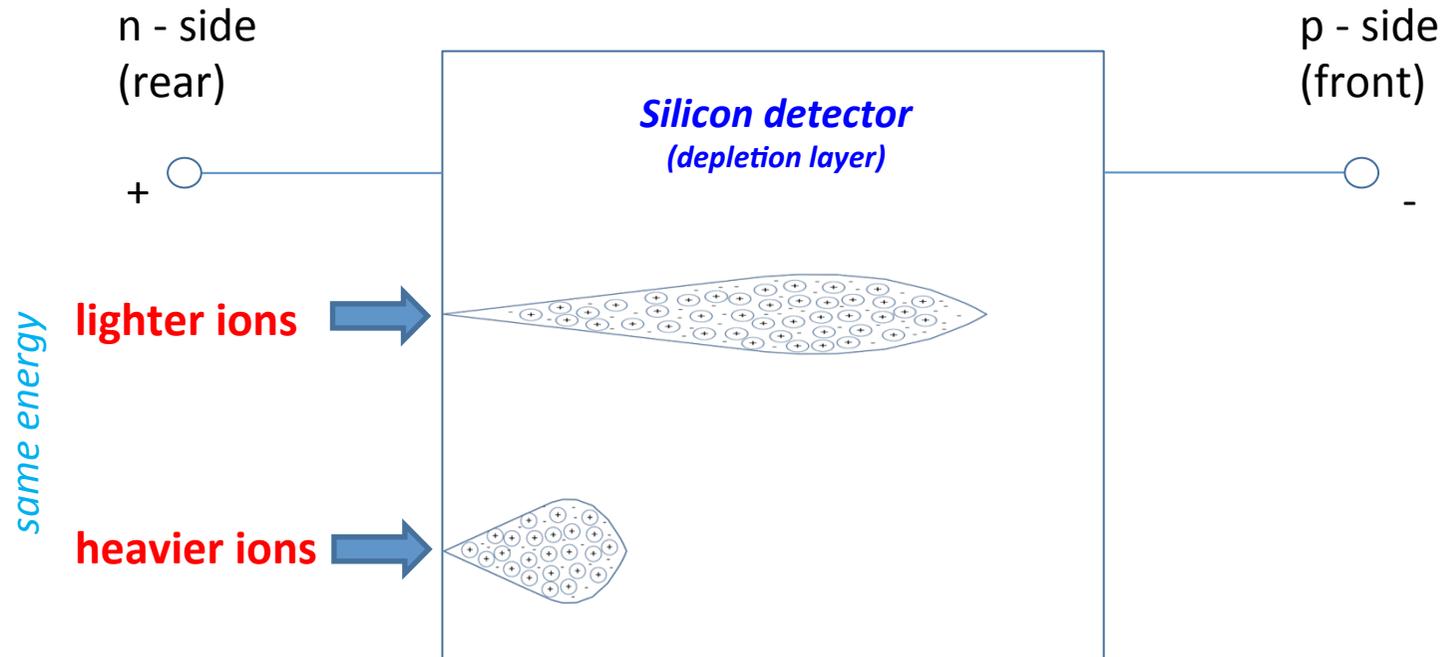
# Particle discrimination by rear side injection mode



The charge collection time depends on  $E, Z, A$ .



## Particle discrimination by rear side injection mode



If

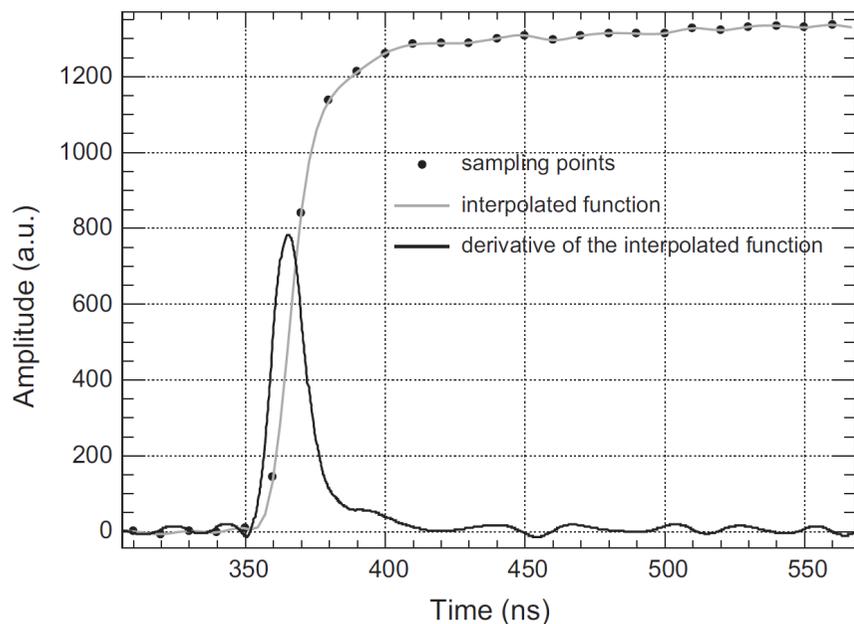
- ✓ Injection in the rear (ohmic) side
- ✓ High E field gradient (low overvoltage)
- ✓ High E uniformity → neutron-transmutation-doped silicon (NTD)

Pulse Shape



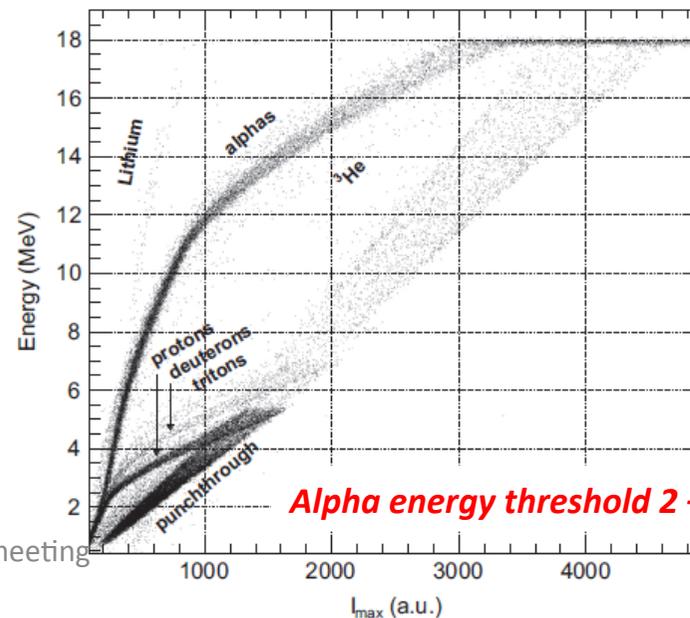
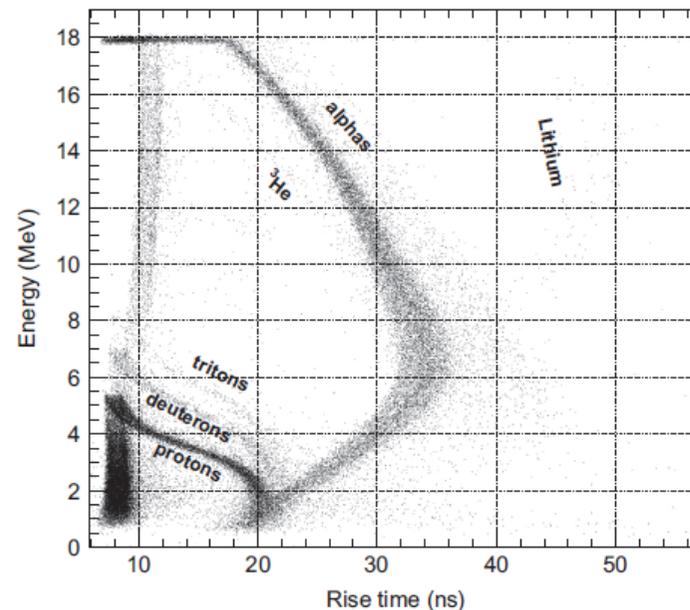
(A,Z)

D. Mengoni et al, NIM A764 (2014) 241–246

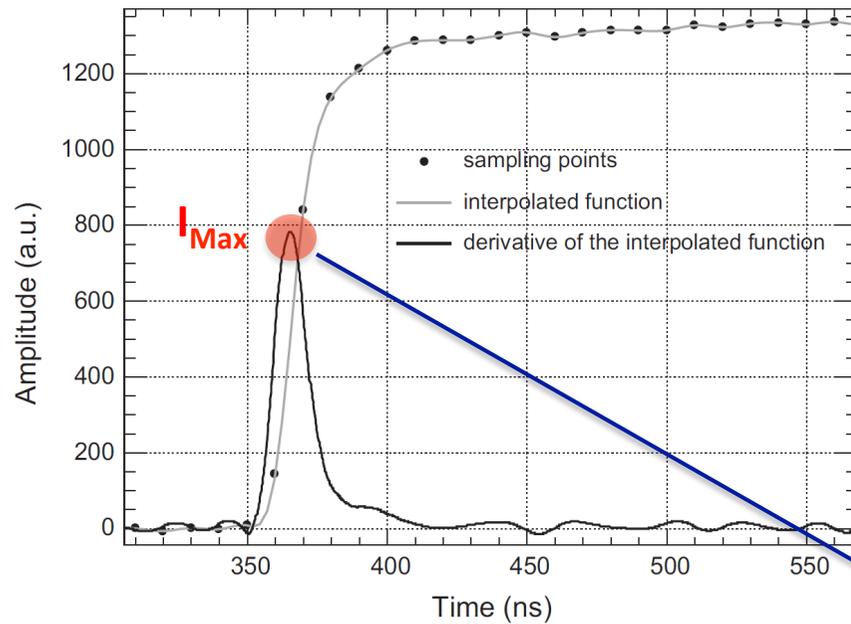


## Current signal by:

- *fast current amplifier*
- *derivative of the charge signal*

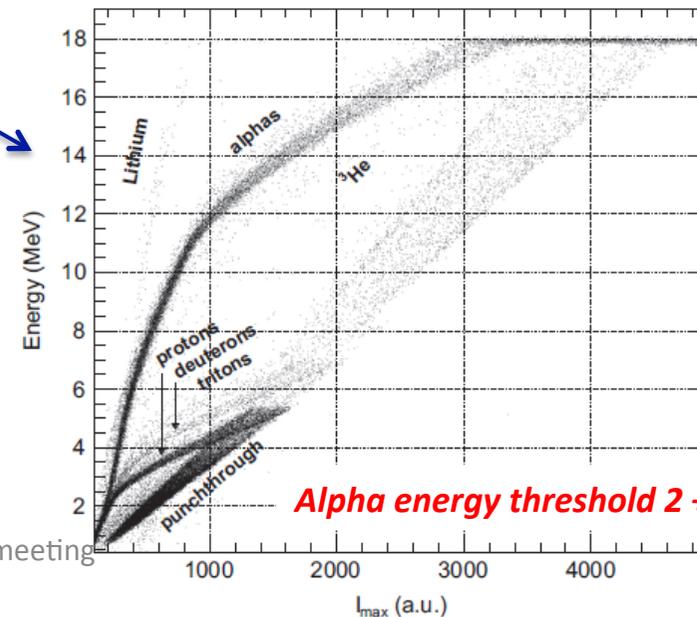
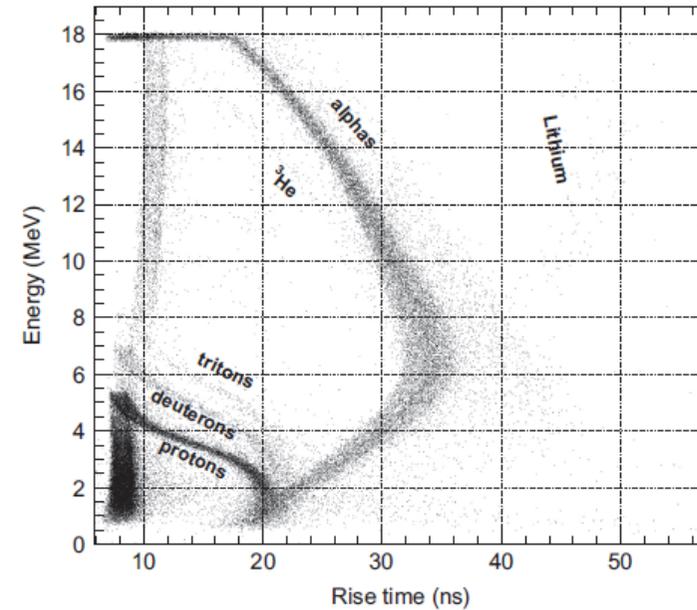


D. Mengoni et al, NIM A764 (2014) 241–246

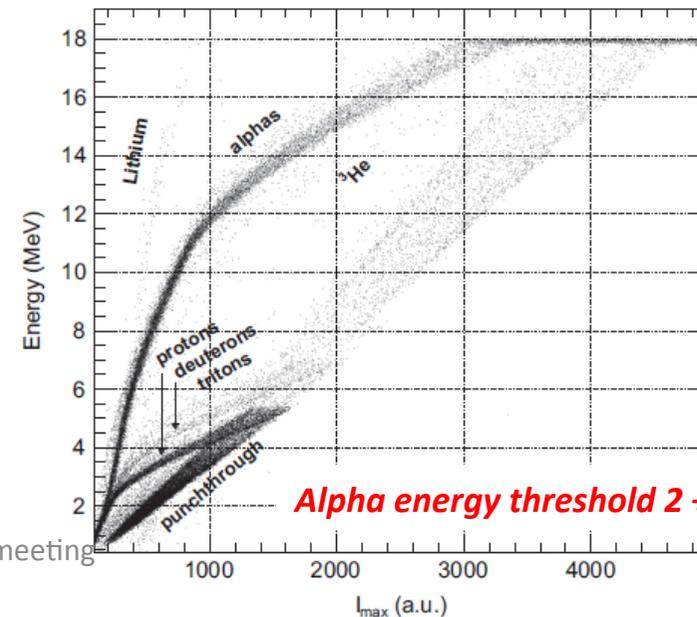
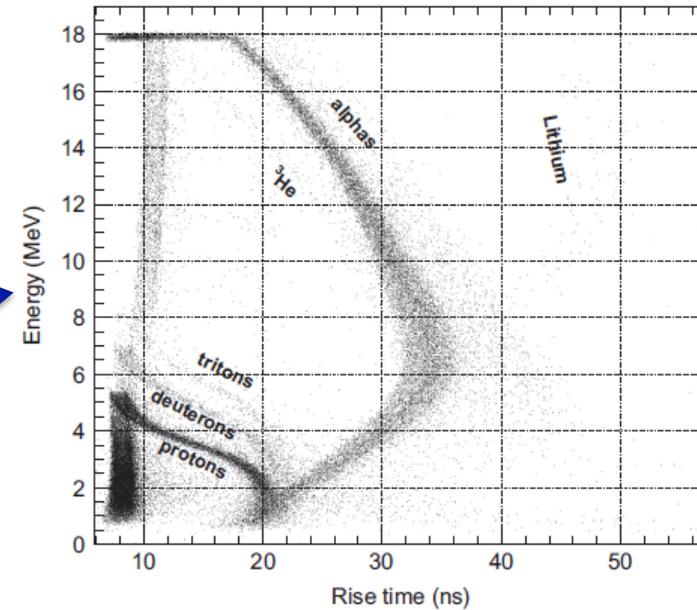
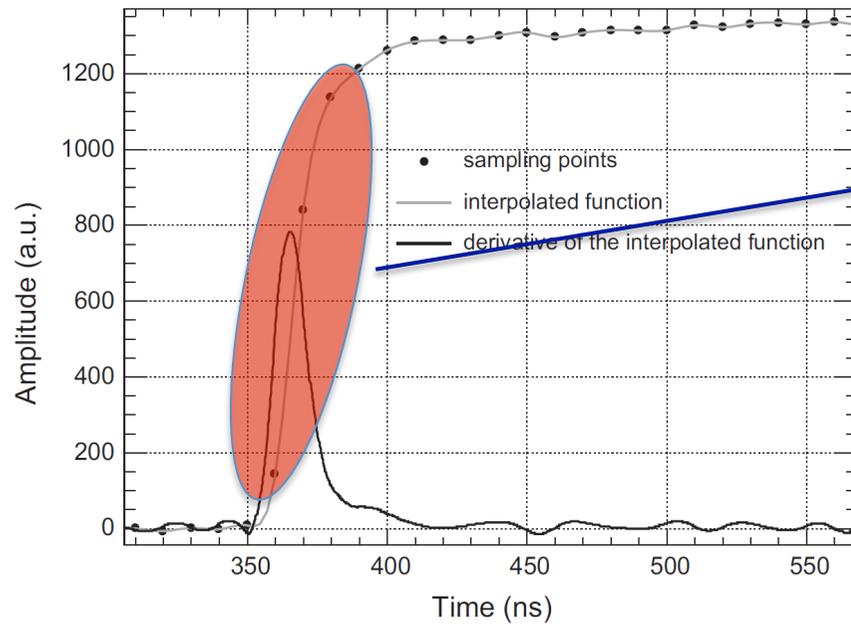


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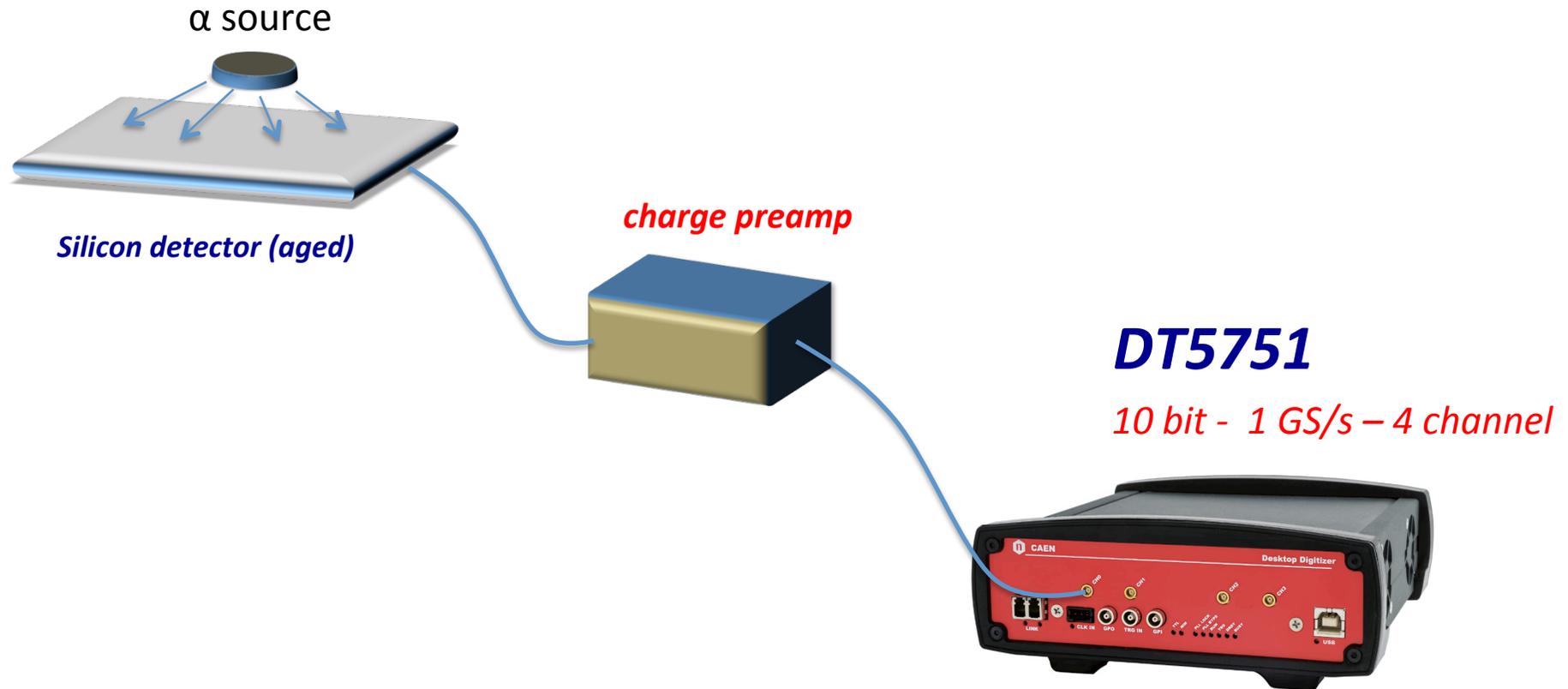


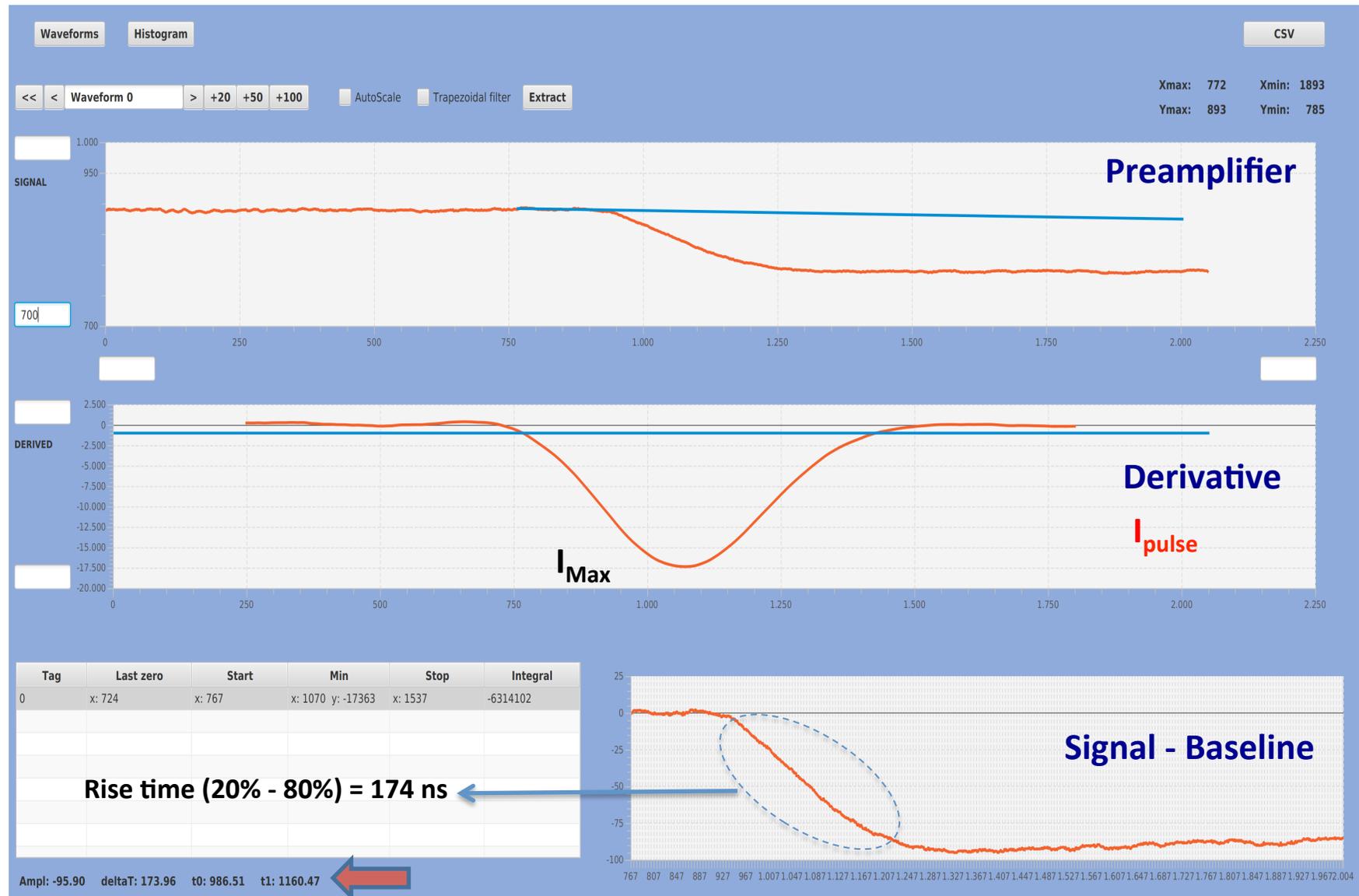
D. Mengoni et al, NIM A764 (2014) 241–246

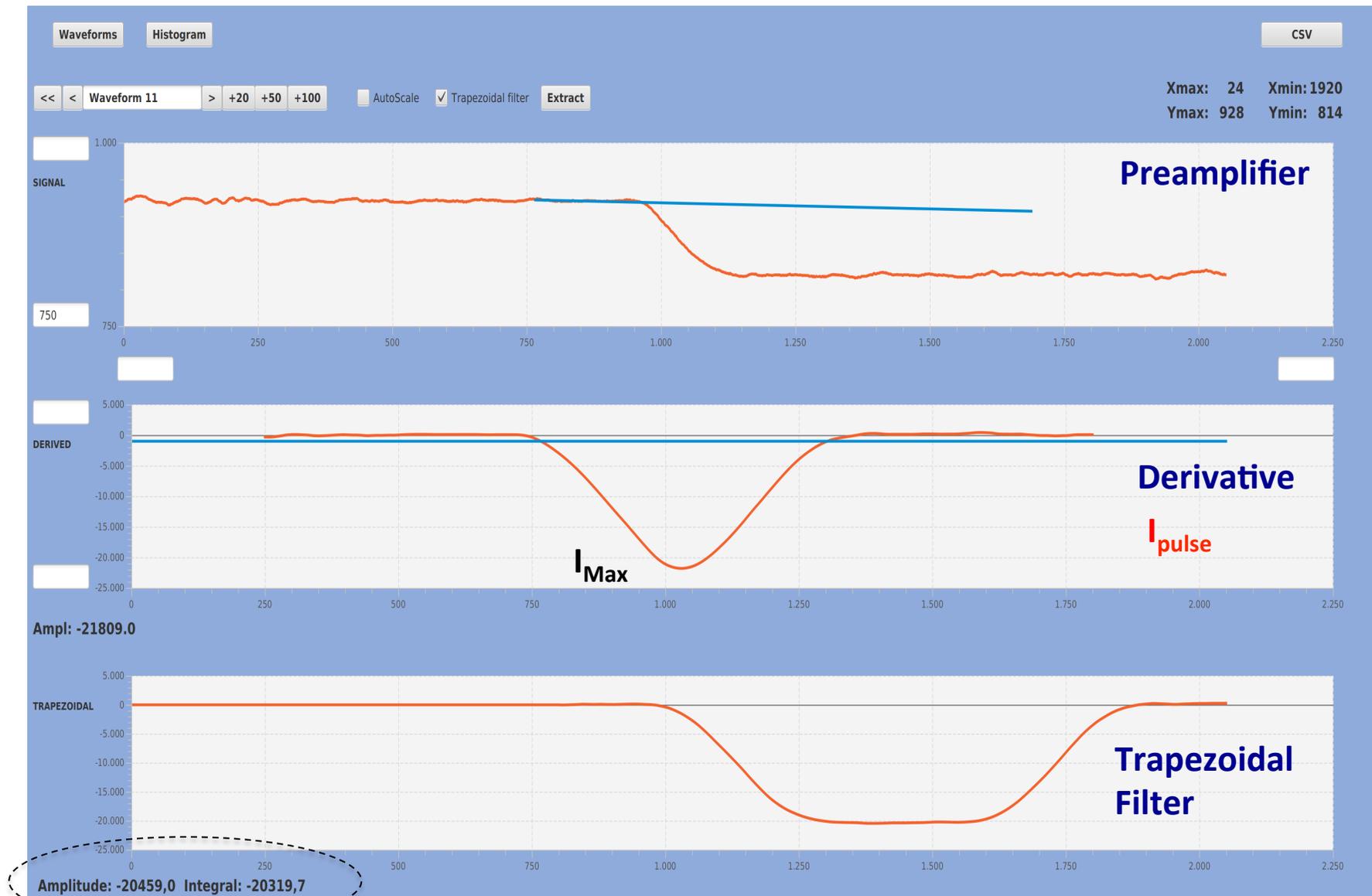


### Current signal by:

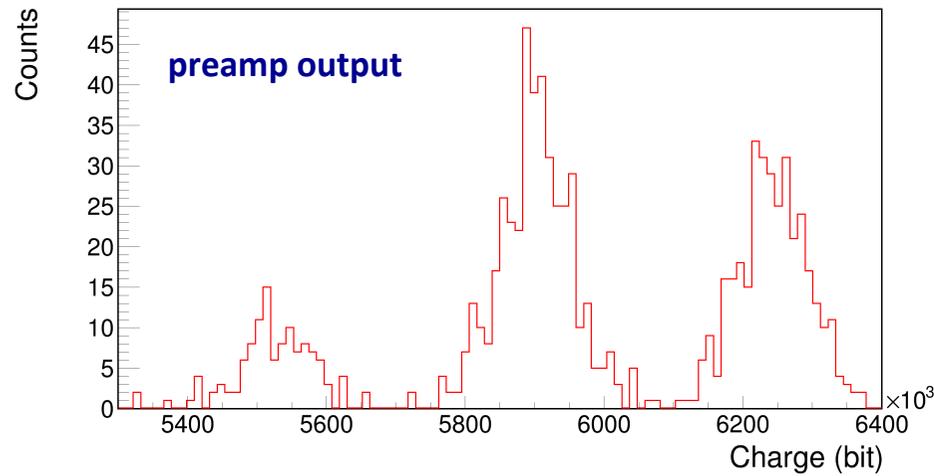
- *fast current amplifier*
- *derivative of the charge signal*



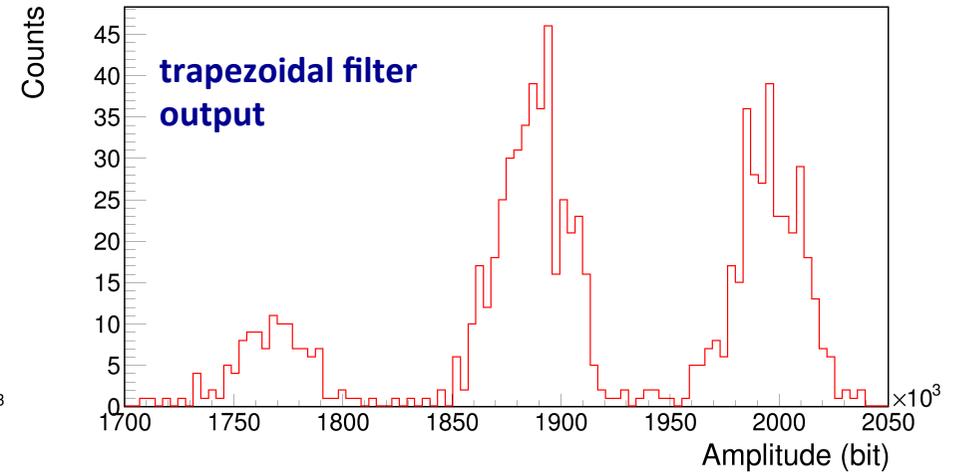




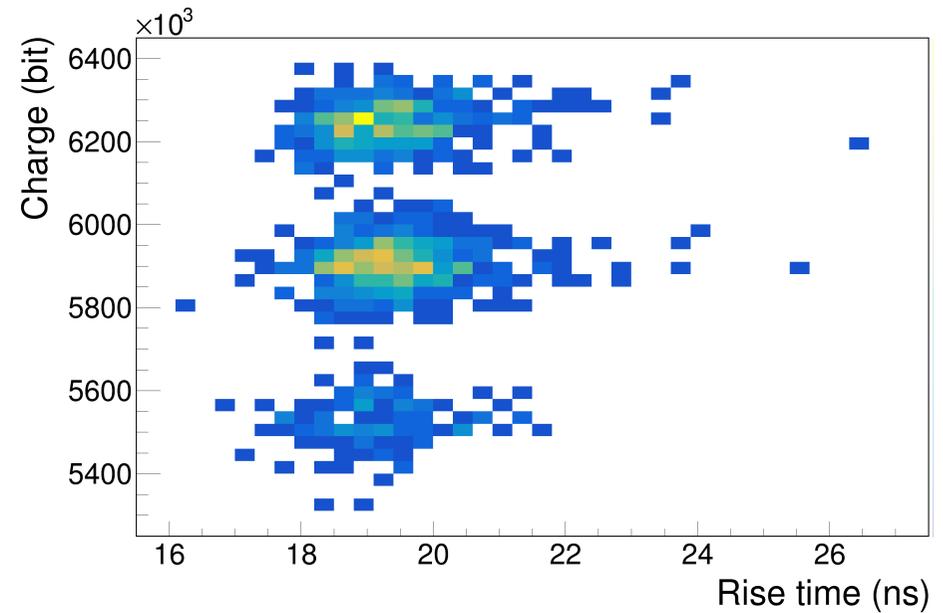
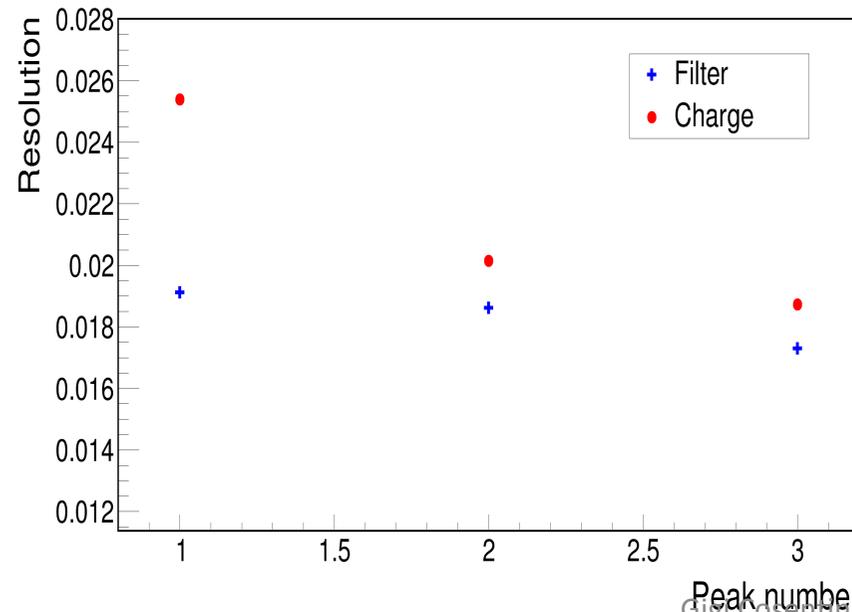
Signal total charge

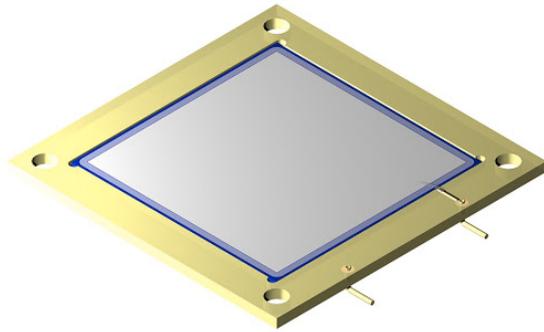


Signal amplitude with filter

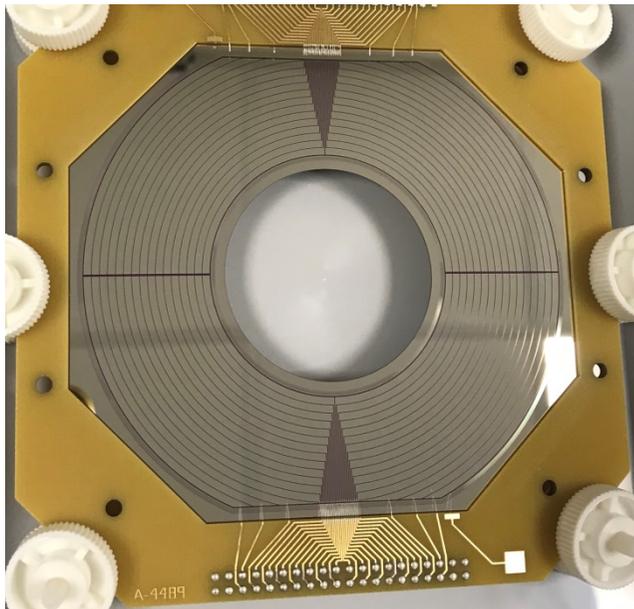


Resolution for each peak





NTD Silicon detector - Single PAD



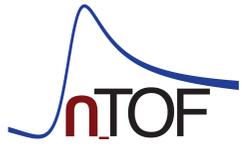
## Micron Semiconductor

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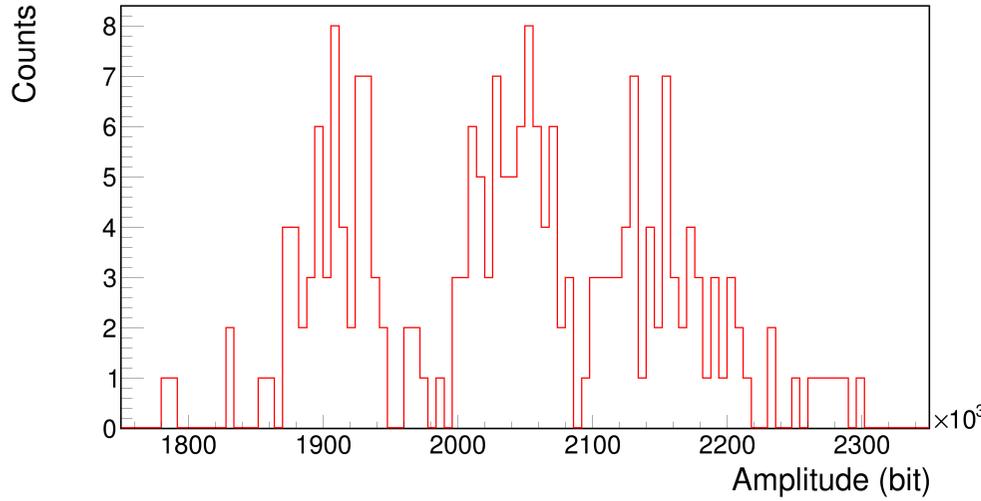


**Fase 2**

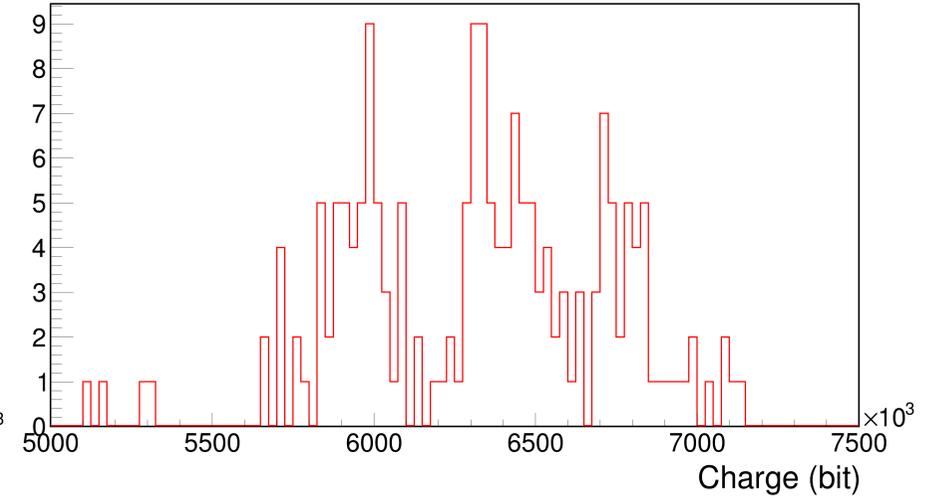
- **Messa a punto del software di analisi con ulteriori misure alpha – silicio NTD 3x3cm<sup>2</sup>**
- **Discriminazione <sup>3</sup>H – alpha con sorgente di neutroni e <sup>6</sup>LiF layer**
- **Realizzazione PCB per il rivelatore anulare**
- **Test con rivelatore anulare e sorgenti**



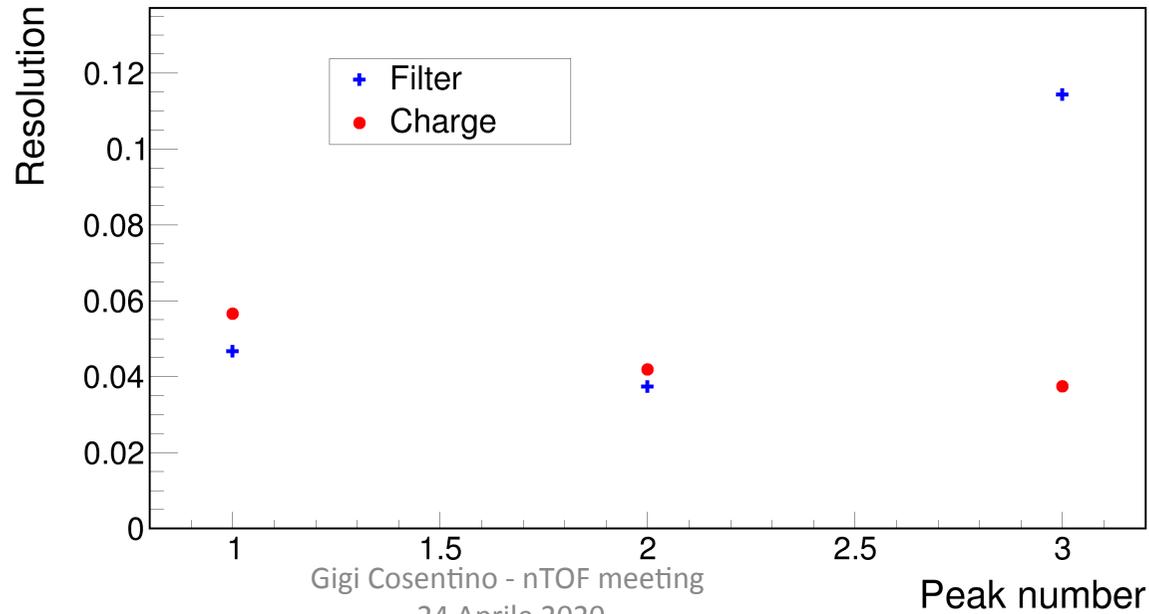
Signal amplitude with filter



Signal total charge



Resolution for each peak

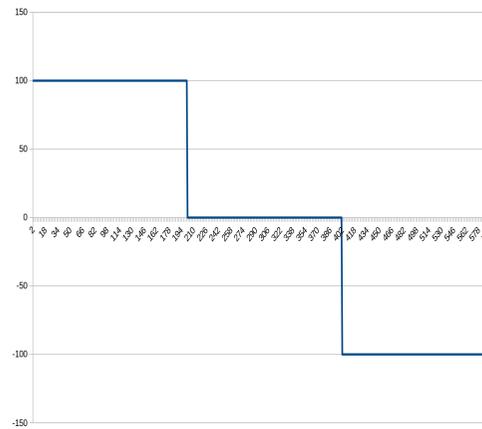


# Trapezoidal filter - Convolution

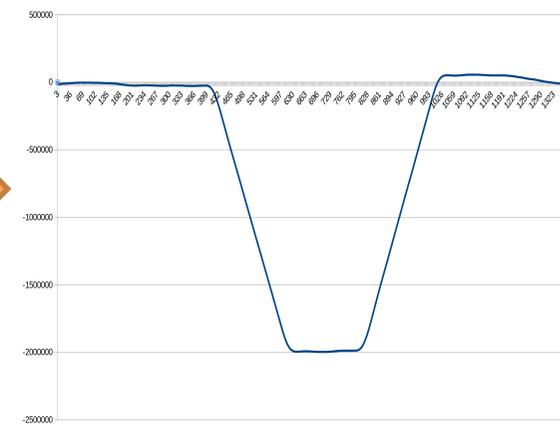
Original signal



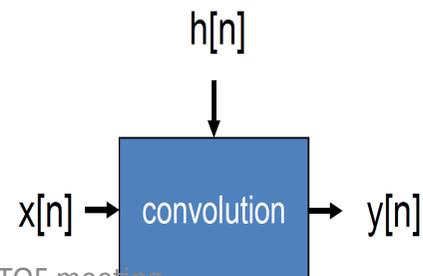
Bipolar filter

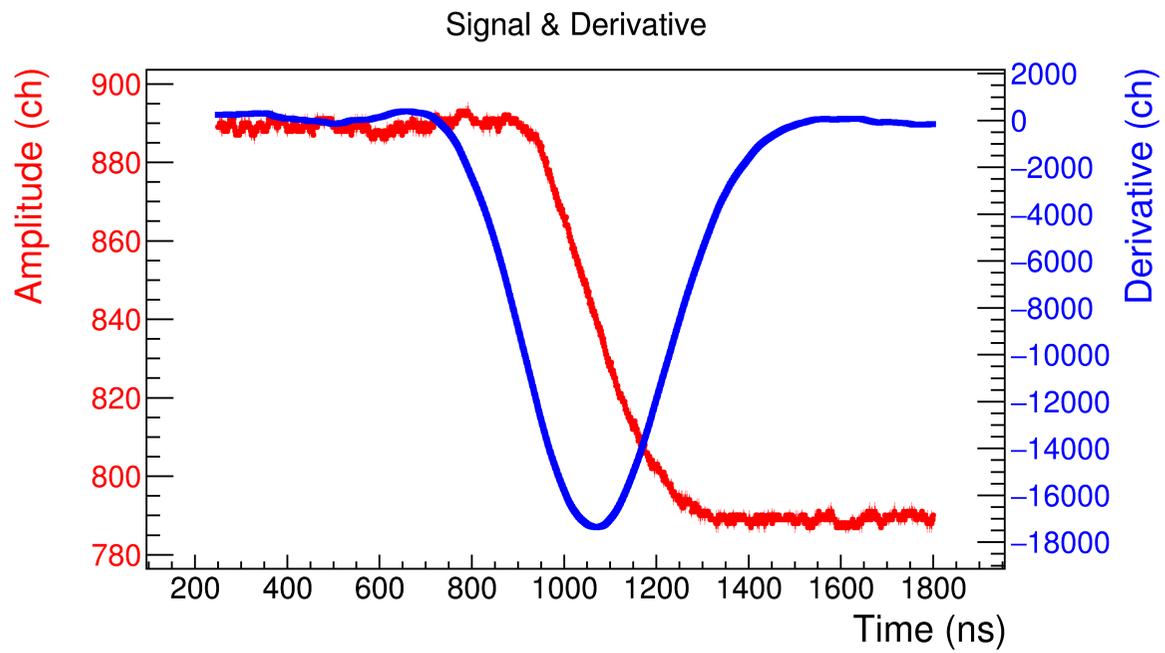


Trapezoidal output



$$y[n] = \sum_{k=0}^N h[k] \cdot x[n-k]$$





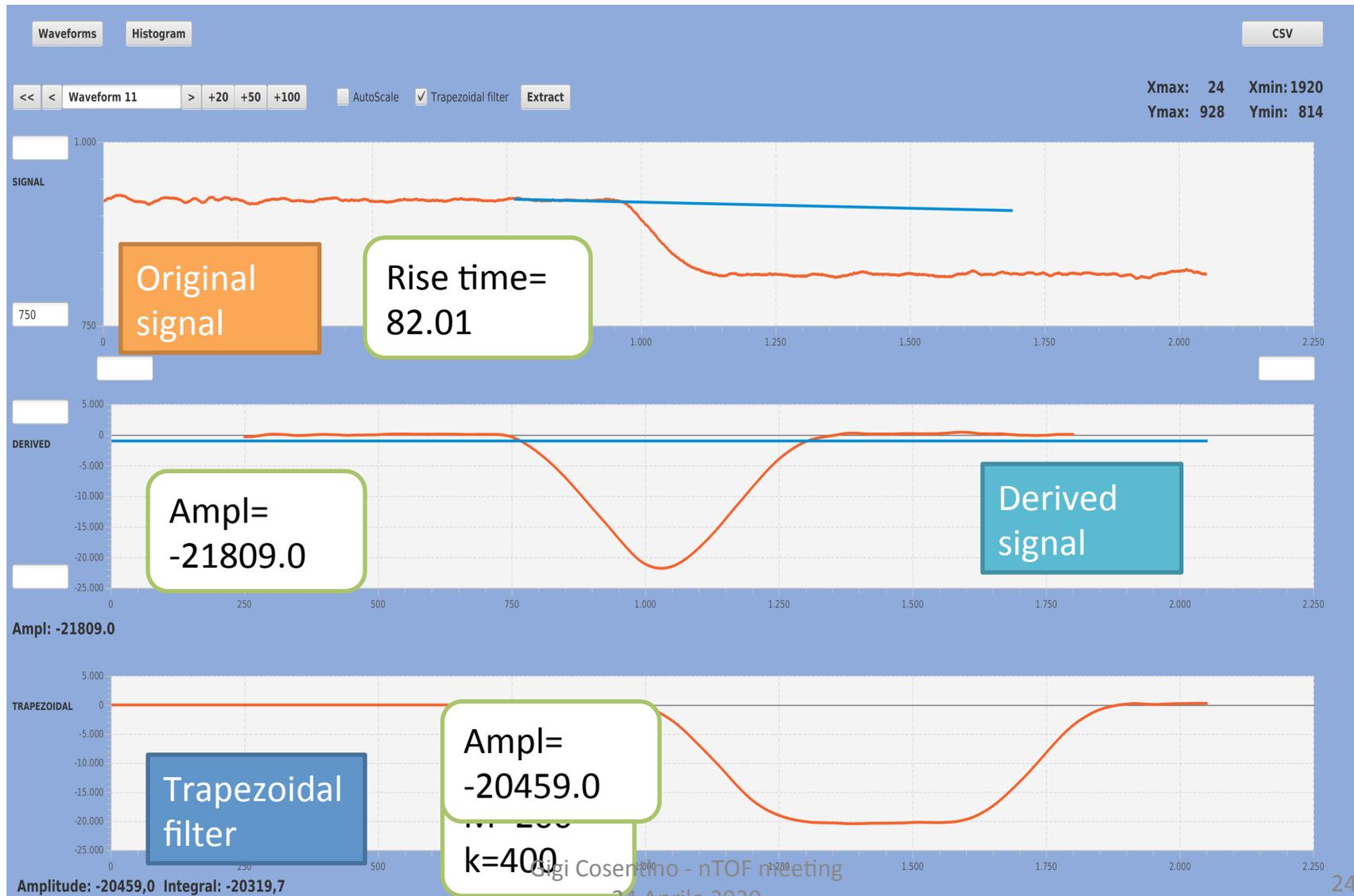
# Signal without background calculation

$s(i) = v(i) - \text{PolynomialCurveFitter}(i)$

```
for(int i=startx; i<2*stopx-minderx; i++){  
    ((XYChart.Series)linechart.getData().get(2)).getData().add(new XYChart.Data(i, bestFit[1]*i+bestFit[0]));  
    backgmap.put(i, bestFit[1]*i+bestFit[0]);  
}
```

```
for(int i=start; i<2*stop-xmin; i++){  
  
    Double snew=0.0;  
    if(i<((XYChart.Series)linechart.getData().get(0)).getData().size())  
        snew=(Integer)((Data)((XYChart.Series)linechart.getData().get(0)).getData().get(i)).getYValue()-backgmap.get(i);  
  
    ((XYChart.Series)signalsubchart.getData().get(0)).getData().add(new XYChart.Data(i, snew));  
}
```

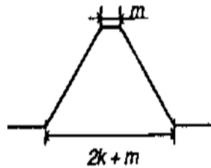
# Trapezoidal Filter



# Trapezoidal Filter

$$s(n)=s(n-1)+v(n)-v(n-k)-v(n-l)+v(n-l-k)$$

where  $l=k+m$



```
for(int i=0; i<arr.length; i++){
    if(i<2*k+m){
        s.add(0.0);
        ((XYChart.Series)trapezchart.getData().get(0)).getData().add(new XYChart.Data(i, 0));
    }
    else{
        double val=s.get(i-1)+Integer.parseInt(arr[i])-Integer.parseInt(arr[i-k])
            -Integer.parseInt(arr[i-k-m])+Integer.parseInt(arr[i-m-2*k]);
        s.add(val);

        ((XYChart.Series)trapezchart.getData().get(0)).getData().add(new XYChart.Data(i, val));
    }
}
/*
```

